

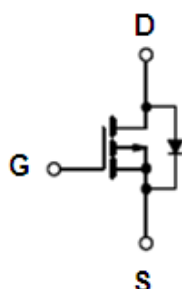
## 1. Features

- n  $R_{DS(on)}=78m\Omega$ (typ) @  $V_{GS}=10V$
- n 100% EAS guaranteed
- n Green device available
- n Super low gate charge
- n Excellent Cdv/dt effect decline
- n Advanced high cell density trench technology

## 2. Description

The KIA23P10A uses advanced trench MOSFET technology to provide excellent  $R_{DS(ON)}$  and gate charge for use in a wide variety of other applications. The KIA23P10A meet the RoHS and Green product requirement, 100% EAS guaranteed with full function reliability approved.

## 3. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

## 4. Absolute maximum ratings

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DS}$	-100	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current $V_{GS}@-10V^1$	$I_D$	$T_C=25^\circ C$	-23
		$T_C=100^\circ C$	-16
Pulsed drain current <sup>2</sup>	$I_{DM}$	-75	A
Single pulse avalanche energy <sup>3</sup>	EAS	157.2	mJ
Avalanche current	$I_{AS}$	18.9	A
Total power dissipation <sup>4</sup>	$P_D$	96	W
Junction and storage temperature range	$T_J, T_{STG}$	-55 to 150	$^\circ C$
Thermal resistance-junction to ambient <sup>1</sup>	$R_{\theta JA}$	62	$^\circ C/W$
Thermal resistance-junction to case <sup>1</sup>	$R_{\theta JC}$	1.3	$^\circ C/W$

## 5. Electrical characteristics

(T<sub>J</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-100	-	-	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =-100V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	-	-	-50	μA
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	-1.2	-1.7	-2.5	V
Static drain-source on- resistance <sup>2</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A	-	78	95	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-8A	-	86	110	
Forward transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A	-	24	-	S
Total gate charge	Q <sub>g</sub>	V <sub>DS</sub> =-50V, V <sub>GS</sub> =-10V I <sub>D</sub> =-20A	-	44.5	-	nC
Gate-source charge	Q <sub>gs</sub>		-	9.13	-	
Gate-drain charge	Q <sub>gd</sub>		-	5.93	-	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =-50V, R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =-10V I <sub>D</sub> =-10A	-	12	-	ns
Rise time	t <sub>r</sub>		-	27.4	-	
Turn-off delay time	t <sub>d(off)</sub>		-	79	-	
Fall time	t <sub>f</sub>		-	53.6	-	
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =-20V F=1.0MHZ	-	3029	-	pF
Output capacitance	C <sub>oss</sub>		-	129	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	76	-	
Diode characteristics						
Continuous source current <sup>1,5</sup>	I <sub>S</sub>	V <sub>G</sub> =V <sub>D</sub> =0V, Force current	-	-	-23	A
Diode forward voltage <sup>2</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A, T <sub>J</sub> =25°C	-	-	1.2	V
Reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> =-8A, dI/dt=100A/us, T <sub>J</sub> =25°C	-	38.7	-	nS
Reverse recovery charge	Q <sub>rr</sub>		-	22.4	-	nC

Note:1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

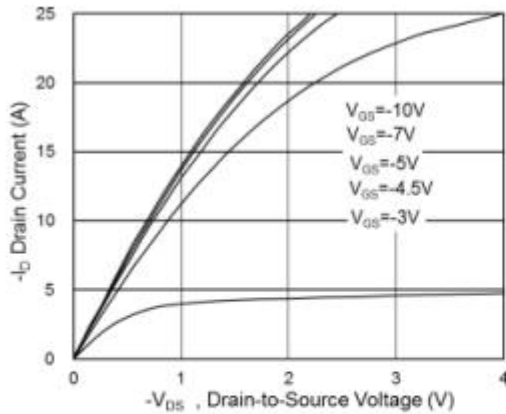
2. The data tested by pulsed, pulse width ≤300us, duty cycle ≤2%.

3. The EAS data shows Max.rating. The test condition is V<sub>DD</sub>=-25V, V<sub>GS</sub>=-10V, L=0.88mH, I<sub>AS</sub>=-18.9A.

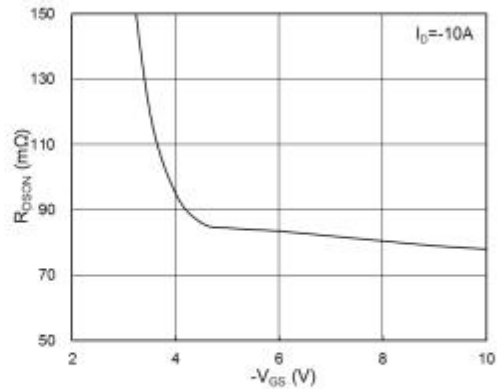
4. The power dissipation is limited by 150 °C junction temperature.

5. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

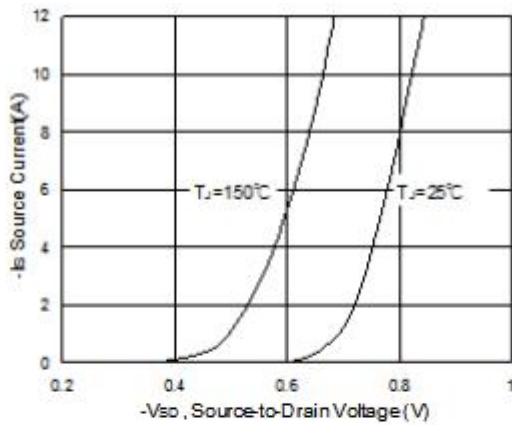
**6. Test circuits and waveforms**



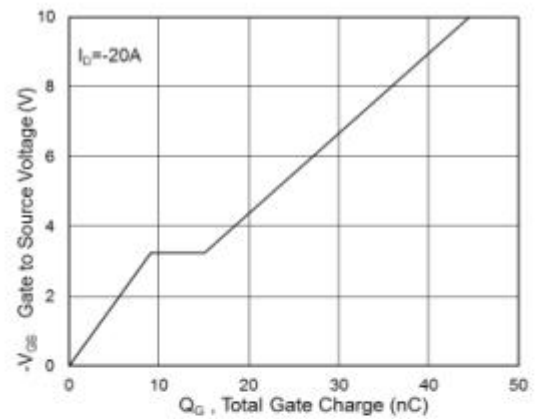
**Fig.1 Typical Output Characteristics**



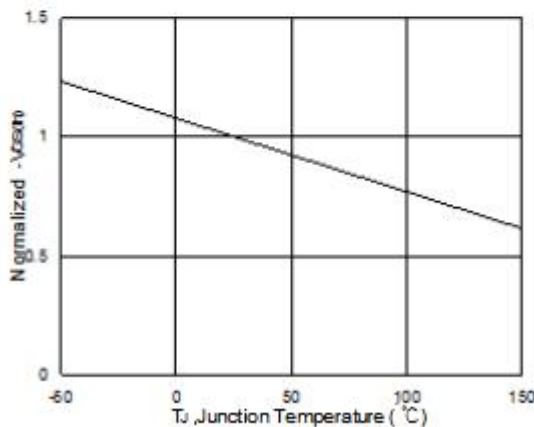
**Fig.2 On-Resistance vs. G-S Voltage**



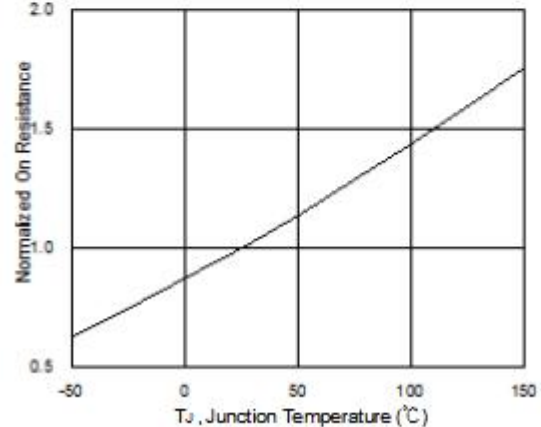
**Fig.3 Typical S-D Diode Forward Voltage**



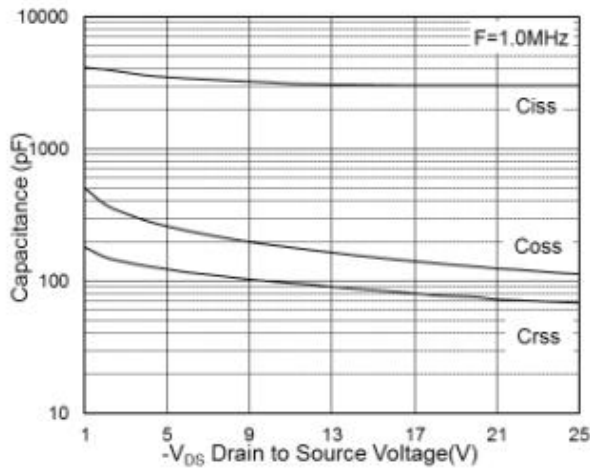
**Fig.4 Gate-Charge Characteristics**



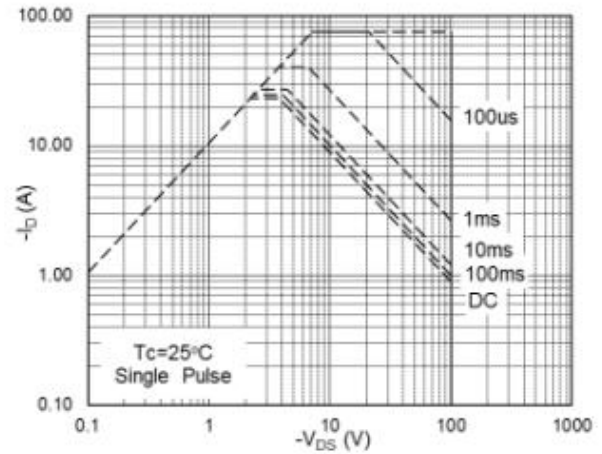
**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



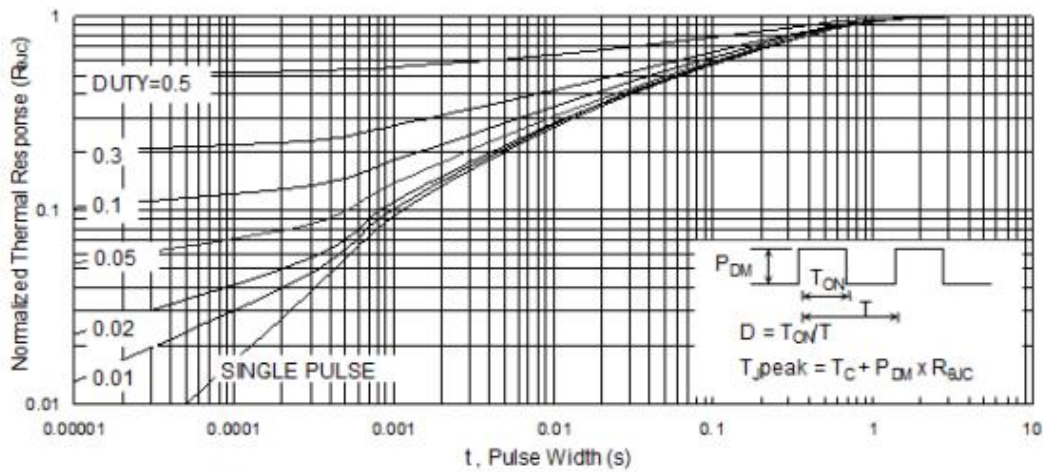
**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**



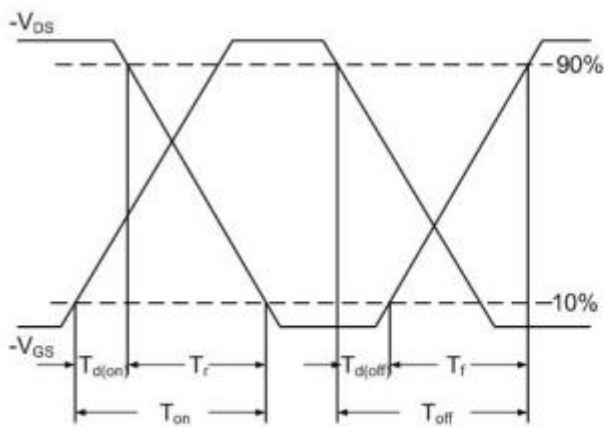
**Fig.7 Capacitance**



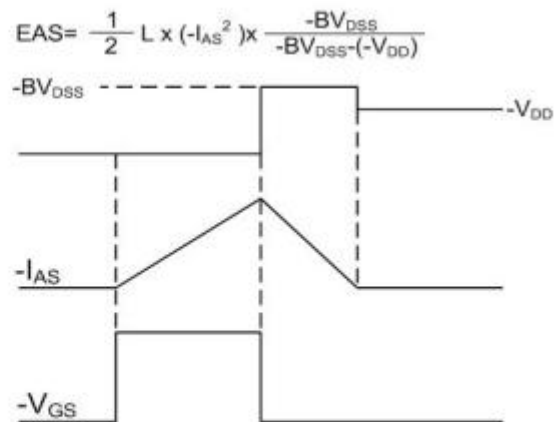
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Waveform**